

SN5473, SN54LS73A, SN7473, SN74LS73A DUAL J-K FLIP-FLOPS WITH CLEAR

SDLS118 – DECEMBER 1983 – REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

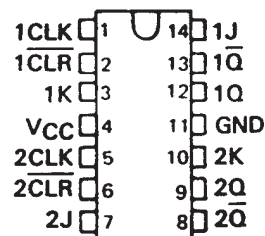
description

The '73, and 'H73, contain two independent J-K flip-flops with individual J-K, clock, and direct clear inputs. The '73, and 'H73, are positive pulse-triggered flip-flops. J-K input is loaded into the master while the clock is high and transferred to the slave on the high-to-low transition. For these devices the J and K inputs must be stable while the clock is high.

The 'LS73A contains two independent negative-edge-triggered flip-flops. The J and K inputs must be stable one setup time prior to the high-to-low clock transition for predictable operation. When the clear is low, it overrides the clock and data inputs forcing the Q output low and the \bar{Q} output high.

The SN5473, SN54H73, and the SN54LS73A are characterized for operation over the full military temperature range of -55°C to 125°C . The SN7473, and the SN74LS73A are characterized for operation from 0°C to 70°C .

SN5473, SN54LS73A . . . J OR W PACKAGE
SN7473 . . . N PACKAGE
SN74LS73A . . . D OR N PACKAGE
(TOP VIEW)



'73
FUNCTION TABLE

INPUTS				OUTPUTS	
CLR	CLK	J	K	Q	\bar{Q}
L	X	X	X	L	H
H	\downarrow	L	L	Q_0	\bar{Q}_0
H	\downarrow	H	L	H	L
H	\downarrow	L	H	L	H
H	\downarrow	H	H	TOGGLE	TOGGLE

'LS73A
FUNCTION TABLE

INPUTS				OUTPUTS	
CLR	CLK	J	K	Q	\bar{Q}
L	X	X	X	L	H
H	\downarrow	L	L	Q_0	\bar{Q}_0
H	\downarrow	H	L	H	L
H	\downarrow	L	H	L	H
H	\downarrow	H	H	TOGGLE	TOGGLE
H	H	X	X	Q_0	\bar{Q}_0

FOR CHIP CARRIER INFORMATION,
CONTACT THE FACTORY

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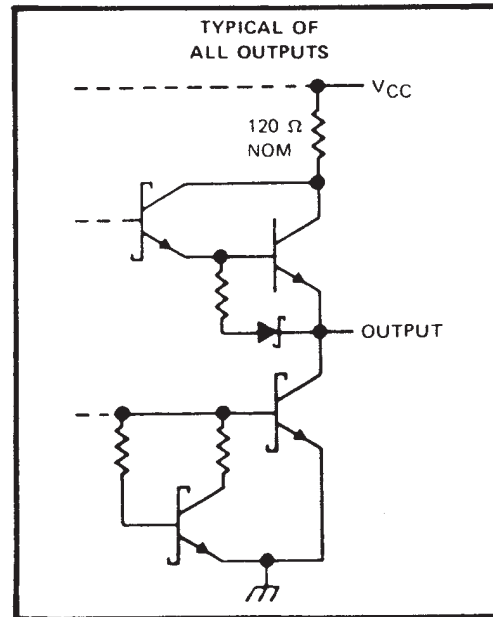
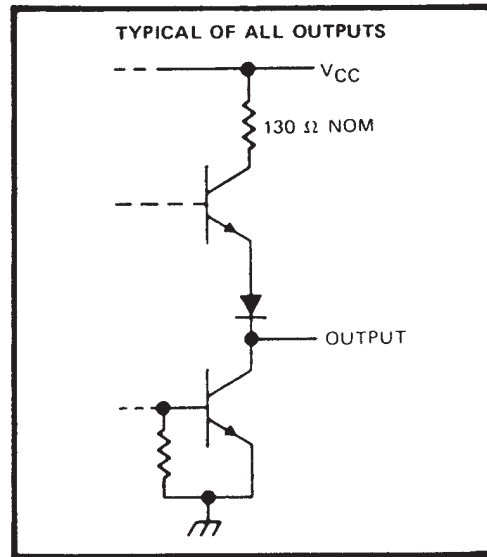
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logic symbols†



†These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

schematics of inputs and outputs



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logic diagrams (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (See Note 1)	7 V
Input voltage: '73	5.5 V
'LS73A	7 V
Operating free-air temperature range: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



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recommended operating conditions

		SN5473			SN7473			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX		
V_{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V	
V_{IH}	High-level input voltage	2			2			V	
V_{IL}	Low-level input voltage			0.8			0.8	V	
I_{OH}	High-level output current			-0.4			-0.4	mA	
I_{OL}	Low-level output current			16			16	mA	
t_w	Pulse duration	CLK high		20			20	ns	
		CLK low		47			47		
		\overline{CLR} low		25			25		
t_{su}	Input setup time before CLK \uparrow			0			0	ns	
t_h	Input hold time data after CLK \downarrow			0			0	ns	
T_A	Operating free-air temperature			-55		125	0	70	$^{\circ}C$

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]	SN5473			SN7473			UNIT
		MIN	TYP [‡]	MAX	MIN	TYP [‡]	MAX	
V_{IK}	$V_{CC} = \text{MIN}$, $I_I = -12 \text{ mA}$			-1.5			-1.5	V
V_{OH}	$V_{CC} = \text{MIN}$, $V_{IH} = 2 \text{ V}$, $V_{IL} = 0.8 \text{ V}$, $I_{OH} = -0.4 \text{ mA}$	2.4	3.4		2.4	3.4		V
V_{OL}	$V_{CC} = \text{MIN}$, $V_{IH} = 2 \text{ V}$, $V_{IL} = 0.8 \text{ V}$, $I_{OL} = 16 \text{ mA}$		0.2	0.4		0.2	0.4	V
I_I	$V_{CC} = \text{MAX}$, $V_I = 5.5 \text{ V}$			1			1	mA
I_{IH}	J or K			40			40	μA
	\overline{CLR} or CLK			80			80	
I_{IL}	J or K			-1.6			-1.6	mA
	\overline{CLR}			-3.2			-3.2	
	CLK			-3.2			-3.2	
I_{OS} [§]	$V_{CC} = \text{MAX}$	-20		-57	-18		-57	mA
I_{CC} [¶]	$V_{CC} = \text{MAX}$, See Note 2		10	20		10	20	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}C$.

[§] Not more than one output should be shorted at a time.

[¶] Average per flip-flop.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and \overline{Q} outputs high in turn. At the time of measurement, the clock input is grounded.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}C$ (see note 3)

PARAMETER [#]	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f_{max}			$R_L = 400 \Omega$, $C_L = 15 \text{ pF}$	15	20		MHz
t_{PLH}	\overline{CLR}	\overline{Q}			16	25	ns
t_{PHL}		Q			25	40	ns
t_{PLH}	CLK	Q or \overline{Q}			16	25	ns
t_{PHL}						25	40

[#] f_{max} = maximum clock frequency; t_{PLH} = propagation delay time, low-to-high-level output; t_{PHL} = propagation delay time, high-to-low-level output.

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



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recommended operating conditions

		SN54LS73A			SN74LS73A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.7			0.8	V
I_{OH}	High-level output current			-0.4			-0.4	mA
I_{OL}	Low-level output current			4			8	mA
f_{clock}	Clock frequency	0		30	0		30	MHz
t_w	Pulse duration	CLK high		20	20		ns	
		CLR low		25	20			
t_{su}	Set up time-before CLK ↓	data high or low		20	20		ns	
		CLR inactive		20	20			
t_h	Hold time-data after CLK ↓	0			0			ns
T_A	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†		SN54LS73A		SN74LS73A		UNIT
				MIN	TYP‡	MAX	MIN	
V_{IK}		$V_{CC} = \text{MIN}$, $I_I = -18 \text{ mA}$		-1.5		-1.5		V
V_{OH}		$V_{CC} = \text{MIN}$, $I_{OH} = -0.4 \text{ mA}$	$V_{IH} = 2 \text{ V}$, $V_{IL} = \text{MAX}$,	2.5	3.4	2.7	3.4	V
V_{OL}		$V_{CC} = \text{MIN}$, $I_{OL} = 4 \text{ mA}$	$V_{IL} = \text{MAX}$, $V_{IH} = 2 \text{ V}$,	0.25	0.4	0.25	0.4	V
		$V_{CC} = \text{MIN}$, $I_{OL} = 8 \text{ mA}$	$V_{IL} = \text{MAX}$, $V_{IH} = 2 \text{ V}$,			0.35	0.5	
I_I	J or K	$V_{CC} = \text{MAX}$, $V_I = 7 \text{ V}$		0.1		0.1	mA	
	CLR			0.3		0.3		
	CLK			0.4		0.4		
I_{IH}	J or K	$V_{CC} = \text{MAX}$, $V_I = 2.7 \text{ V}$		20		20	μA	
	CLR			60		60		
	CLK			80		80		
I_{IL}	J or K	$V_{CC} = \text{MAX}$, $V_I = 0.4 \text{ V}$		-0.4		-0.4	mA	
	CLR or CLK			-0.8		-0.8		
$I_{OS}§$		$V_{CC} = \text{MAX}$, See Note 4		-20		-20		mA
I_{CC} (Total)		$V_{CC} = \text{MAX}$, See Note 2		4	6	4	6	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^\circ\text{C}$.

§ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and \bar{Q} outputs high in turn. At the time of measurement, the clock input is grounded.

NOTE 4: For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with $V_O = 2.25 \text{ V}$ and 2.125 V for the 54 family and the 74 family, respectively, with the minimum and maximum limits reduced to one half of their stated values.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^\circ\text{C}$ (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
f_{max}					30	45		MHz
t_{PLH}	CLR or CLK	Q or \bar{Q}	$R_L = 2 \text{ k}\Omega$,	$C_L = 15 \text{ pF}$		15	20	ns
t_{PHL}						15	20	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



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